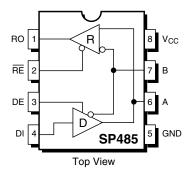


# **SP481E/SP485E**

# Enhanced Low Power Half-Duplex RS-485 Transceivers

## **FEATURES**

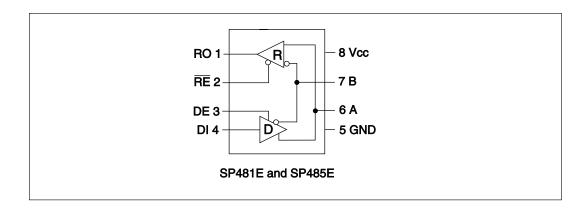
- +5V Only
- Low Power BiCMOS
- Driver/Receiver Enable for Multi-Drop configurations
- Low Power Shutdown Mode (SP481E)
- Enth (World rEar) Desprey (World bons: ±15KV IEC1000-4-2 Air Discharge +8KV IEC1000-4-2 Contact Discharge



SP481E and SP485E Pinout (Top View) Now Available in Lead Free Packaging

#### DESCRIPTION

The **SP481E** and the **SP485E** are a family of half-duplex transceivers that meet the specifications of RS-485 and RS-422 serial protocols with enhanced ESD performance. The ESD tolerance has been improved on these devices to over  $\pm 15$ KV for both Human Body Model and IEC1000-4-2 Air Discharge Method. These devices are pin-to-pin compatible with Sipex's SP481 and SP485 devices as well as popular industry standards. As with the original versions, the **SP481E** and the **SP485E** feature Sipex's BiCMOS design allowing low power operation without sacrificing performance. The **SP481E** and **SP485E** meet the requirements of the RS-485 and RS-422 protocols up to 10Mbps under load. The **SP481E** is equipped with a low power Shutdown mode.



# **ABSOLUTE MAXIMUM RATINGS**

These are stress ratings only and functional operation of the device at these ratings or any other above those indicated in the operation sections of the specifications below is not implied. Exposure to absolute maximum rating conditions for extended periods of time may affect reliability.

V		 	+7V
Input Voltage			
	Logic	 0	.3V to (V <sub>cc</sub> +0.5V)
	Drivers	 0.	3V to (V <sub>cc</sub> +0.5V)
			- ' ' ' ' ' ' ' ' ' ' ' ' ' ' ' ' ' ' '

Output Voltages	
Logic	0.3V to (V <sub>cc</sub> +0.5V
Drivers	
Receivers	
Storage Temperature	65°C to +150°C
Power Dissipation per Package	
8-pin NSOIC (derate 6.60mW/°C above +70°C)	550mW
8-pin PDIP (derate 11.8mW/°C above +70°C)	1000mW

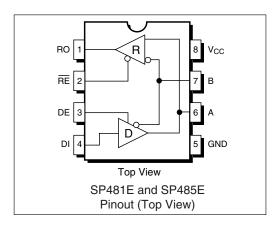
# **ELECTRICAL CHARACTERISTICS**

 $T_{\text{MIN}}$  to  $T_{\text{MAX}}$  and  $V_{\text{CC}}$  = 5V ± 5% unless otherwise noted.

P	ARAMETERS	MIN.	TYP.	MAX.	UNITS	CONDITIONS
SI	P481E/SP485E DRIVER					
D	C Characteristics					
D	ifferential Output Voltage	GND		V <sub>cc</sub>	Volts	Unloaded; $R = \infty$ ; see Figure 1
D	ifferential Output Voltage	2		V <sub>CC</sub>	Volts	with load; $R = 50\Omega$ ; (RS-422);
				00		see Figure 1
D	ifferential Output Voltage	1.5		V <sub>cc</sub>	Volts	with load; $R = 27\Omega$ ; (RS-485); see Figure 1
	hange in Magnitude of Driver					
D	ifferential Output Voltage for					
ı	omplimentary States			0.2	Volts	$R = 27\Omega$ or $R = 50\Omega$ ; see Figure 1
	river Common-Mode					
ı	utput Voltage			3	Volts	$R = 27\Omega$ or $R = 50\Omega$ ; see Figure 1
	put High Voltage	2.0			Volts	Applies to DE, DI, RE
	put Low Voltage			0.8	Volts	Applies to DE, DI, RE
	put Current			±10	μΑ	Applies to DE, DI, RE
	river Short-Circuit Current					
	V <sub>OUT</sub> = HIGH			±250	mA	$-7V \le V_O \le +12V$
-	$V_{OUT} = LOW$			±250	mA	-7V ≤ V <sub>O</sub> ≤ +12V
_	P481E/SP485E DRIVER					
l .	C Characteristics					==
M	laximum Data Rate	10			Mbps	$\overline{RE} = 5V$ , $DE = 5V$ ; $R_{DIFF} = 54\Omega$ ,
_		0.0	0.0			$C_{L1} = C_{L2} = 100pF$
D	river Input to Output	20	30	60	ns	$t_{PLH}$ ; $R_{DIFF} = 54\Omega$ , $C_{L1} = C_{L2} = 100pF$ ;
_	minor languat to Ontorut	00	00	00		see Figures 3 and 5
	river Input to Output SP485EMN ONLY)	20	30	80	ns	$t_{PLH}$ ; $R_{DIFF} = 54\Omega$ , $C_{LI} = C_{L2} = 100 pF$ ; See Figures 3 and 5
(3	SP483EIVIN OINLY)					See Figures 3 and 5
ח	river Input to Output	20	30	60	ns	t : B = 540 C = C = 100nF:
	liver input to Output	20	30	00	115	$t_{PHL}$ ; $R_{DIFF} = 54\Omega$ , $C_{L1} = C_{L2} = 100pF$ ; see Figures 3 and 5
D	river Input to Output	20	30	80	ns	$t_{PHL}$ ; $R_{DIFF} = 54\Omega$ , $C_{L1} = C_{L2} = 100pF$ ;
	SP485EMN ONLY)	20	00		110	see Figures 3 and 5
	river Skew		5	10	ns	see Figures 3 and 5,
_	e. Gilen		Ü			$t_{SKEW} =  t_{DPLH} - t_{DPHL} $
D	river Rise or Fall Time	3	15	40	ns	From 10% to 90%; $R_{DIFF} = 54\Omega$ ,
_						$C_{L1} = C_{L2} = 100 pF$ ; see Figures 3 & 6
D	river Enable to Output High		40	70	ns	$C_1 = 100pF$ ; see Figures 4 & 6; $S_2$
l .	osed					
D	river Enable to Output Low		40	70	ns	C <sub>1</sub> = 100pF; see Figures 4 & 6; S <sub>1</sub>
cl	osed .					
D	river Disable Time from Low		40	70	ns	C <sub>1</sub> = 100pF; see Figures 4 & 6; S <sub>1</sub>
cl	osed					
D	river Disable Time from High		40	70	ns	$C_L = 100pF$ ; see Figures 4 & 6; $S_2$
1			1			

 $\rm T_{MIN}$  to  $\rm T_{MAX}$  and  $\rm V_{CC}$  = 5V  $\pm$  5% unless otherwise noted.

PARAMETER	RS	MIN.	TYP.	MAX.	UNITS	CONDITIONS
SP481E/SP48	35E RECEIVER					
DC Characte	ristics					
Differential In	put Threshold	-0.2		+0.2	Volts	-7V ≤ V <sub>CM</sub> ≤ +12V
	put Threshold	-0.4		+0.4	Volts	-7V ≤ V <sub>CM</sub> ≤ +12V
(SP485EMN	ONLY)					Civi
Input Hystere	sis		20		mV	$V_{CM} = 0V$
Output Voltag	je High	3.5			Volts	$I_0 = -4 \text{mA}, V_{1D} = +200 \text{mV}$
Output Voltag	je Low			0.4	Volts	$I_{O} = +4 \text{mA}, \ V_{ID} = -200 \text{mV}$
Three-State (	High Impedance)					
Output Curre	nt			±1	μΑ	$0.4V \le V_0 \le 2.4V$ ; RE = 5V
Input Resista		12	15		kΩ	-7V ≤ V <sub>CM</sub> ≤ +12V
Input Current	$(A, B); V_{IN} = 12V$			+1.0	mA	$DE = 0V, V_{CC} = 0V \text{ or } 5.25V, V_{IN} = 12V$
Input Current	$(A, B); V_{IN} = -7V$			-0.8	mA	DE = 0V, $V_{CC} = 0V$ or 5.25V, $V_{IN} = -7V$
Short-Circuit	Current	7		95	mA	$0V \le V_O \le V_{CC}$
SP481E/SP4	85E RECEIVER					
AC Characte	ristics					
Maximum Da		10			Mbps	RE = 0V, $DE = 0V$
Receiver Inpu	it to Output	20	45	100	ns	$t_{PLH}$ ; $R_{DIFF} = 54\Omega$ ,
						$C_{L1} = C_{L2} = 100 \text{pF}$ ; Figures 3 & 7
Receiver Inpu	it to Output	20	45	100	ns	$t_{PHL}$ ; $R_{DIFF} = 54\Omega$ ,
						$C_{L1}^{FRL} = C_{L2}^{FRL} = 100 \text{pF}; Figures 3 & 7$
Diff. Receiver	Skew It <sub>PLH</sub> -t <sub>PHL</sub> I		13		ns	$R_{DIFF} = 54\Omega$ ; $C_{L1} = C_{L2} = 100pF$ ;
						Figures 3 & 7
Receiver Ena	ble to					
Output Low			45	70	ns	$C_{RL} = 15pF$ ; Figures 2 & 8; $S_1$ closed
Receiver Ena	ble to		45	70		0 15-5. Figures 0.8.0.0. sleeped
Output High	alala fuana I a		45	70	ns	C <sub>RL</sub> = 15pF; <i>Figures 2 &amp; 8</i> ; S <sub>2</sub> closed
	able from Low		45	70	ns	C <sub>RL</sub> = 15pF; <i>Figures 2 &amp; 8</i> ; S <sub>1</sub> closed
	able from High		45	70	ns	C <sub>RL</sub> = 15pF; <i>Figures 2 &amp; 8;</i> S <sub>2</sub> closed
SP481E						
Shutdown Ti	•		000	000		DE SV DE OV
Time to Shute		50	200	600	ns	RE = 5V, DE = 0V
	from Shutdown		40	100	no.	C = 100nE: Coo Figuros 4 9 6: C algored
to Output Hig	from Shutdown		40	100	ns	$C_L = 100pF$ ; See Figures 4 & 6; $S_2$ closed
to Output Lov			40	100	ns	C <sub>1</sub> = 100pF; See Figures 4 & 6; S <sub>1</sub> closed
Receiver Enab			40	100	113	O <sub>L</sub> = 100pi , <i>Dee i iguies 4 &amp; 0,</i> 3 <sub>1</sub> closed
Shutdown to C			300	1000	ns	C <sub>1</sub> = 15pF; See Figures 2 & 8; S <sub>2</sub> closed
Receiver Enab			000	1000	110	0 = 10p1, 000 / 1ga/002 d 0, 02 01000d
Shutdown to C			300	1000	ns	C <sub>1</sub> = 15pF; See Figures 2 & 8; S <sub>1</sub> closed
	UIREMENTS				1	
Supply Voltage	-	+4.75		+5.25	Volts	
Supply Curre	•	74.75		+5.25	VOILS	
SP481E/485E						
No Load	-		900		μΑ	RE, DI = 0V or $V_{CC}$ ; DE = $V_{CC}$
140 2000			600		μΑ	RE = 0V, DI = 0V or 5V; DE = 0V
SP481E						0., 2. 0. 0. 0., 52 - 0.
Shutdown M	ode			10	μA	DE = 0V, RE=V <sub>CC</sub>
	NTAL AND ME	HANIC	AI.		ļ	
Operating Te		INNO	_			
Commercia		0		+70	°C	
Industrial (_		-40		+70 +85	°C	
muusmall	·/	-40		+125	.c	
,-		T-U	I	T120		
(_M_)	perature	-65		+150	l°C	
(_M_) Storage Tem	oerature	-65		+150	°C	
(_M_)		-65		+150	°C	



# **PIN FUNCTION**

Pin 1 – RO – Receiver Output.

Pin 2 –  $\overline{RE}$  – Receiver Output Enable Active LOW.

Pin 3 – DE – Driver Output Enable Active HIGH.

Pin 4 – DI – Driver Input.

Pin 5 - GND - Ground Connection.

Pin 6 – A – Driver Output/Receiver Input Non-inverting.

Pin 7 – B – Driver Output/Receiver Input Inverting.

Pin 8 – Vcc – Positive Supply 4.75V<Vcc< 5.25V.

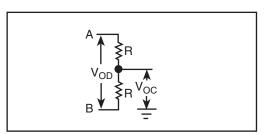


Figure 1. RS-485 Driver DC Test Load Circuit

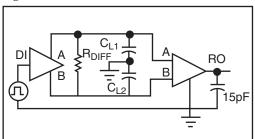


Figure 3. RS-485 Driver/Receiver Timing Test Circuit

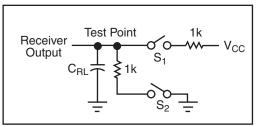


Figure 2. Receiver Timing Test Load Circuit

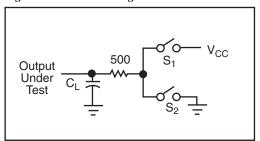


Figure 4. RS-485 Driver Timing Test Load #2 Circuit

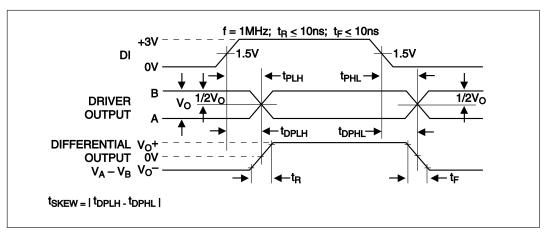


Figure 5. Driver Propagation Delays

I	NPUT	S		OUTI	PUTS
RE	DE	DI	LINE CONDITION	В	A
X	1	1	No Fault	0	1
X	1	0	No Fault	1	0
X	0	X	X	Z	Z
X	1	X	Fault	Z	Z

Table 1.	Transmit	Function	Truth	Table

INP	UTS		OUTPUTS
RE	DE	A - B	R
0	0	+0.2V	1
0	0	-0.2V	0
0	0	Inputs Open	1
1	0	X	Z

Table 2. Receive Function Truth Table

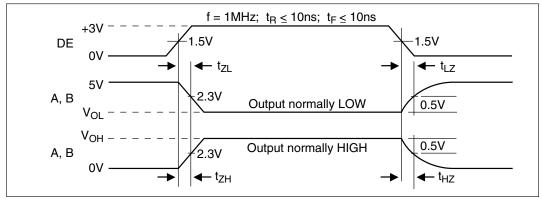


Figure 6. Driver Enable and Disable Times

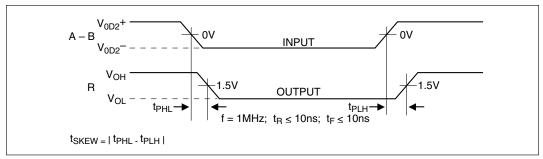


Figure 7. Receiver Propagation Delays

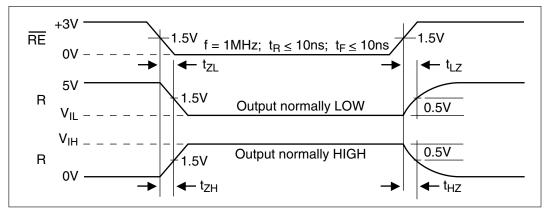


Figure 8. Receiver Enable and Disable Times

#### DESCRIPTION

The **SP481E** and **SP485E** are half-duplex differential transceivers that meet the requirements of RS-485 and RS-422. Fabricated with a Sipex proprietary BiCMOS process, all three products require a fraction of the power of older bipolar designs.

The RS-485 standard is ideal for multi-drop applications and for long-distance interfaces. RS-485 allows up to 32 drivers and 32 receivers to be connected to a data bus, making it an ideal choice for multi-drop applications. Since the cabling can be as long as 4,000 feet, RS-485 transceivers are equipped with a wide (-7V to +12V) common mode range to accommodate ground potential differences. Because RS-485 is a differential interface, data is virtually immune to noise in the transmission line.

#### **Drivers**

The driver outputs of the **SP481E** and **SP485E** are differential outputs meeting the RS-485 and RS-422 standards. The typical voltage output swing with no load will be 0 Volts to +5 Volts. With worst case loading of  $54\Omega$  across the differential outputs, the drivers can maintain greater than 1.5V voltage levels. The drivers of the **SP481E**, and **SP485E** have an enable control line which is active HIGH. A logic HIGH on DE (pin 3) will enable the differential driver outputs. A logic LOW on DE (pin 3) will tri-state the driver outputs.

The transmitters of the **SP481E** and **SP485E** will operate up to at least 10Mbps.

#### Receivers

The **SP481E** and **SP485E** receivers have differential inputs with an input sensitivity as low as  $\pm 200 \text{mV}$ . Input impedance of the receivers is typically  $15 \text{k}\Omega$  ( $12 \text{k}\Omega$  minimum). A wide common mode range of -7V to +12V allows for large ground potential differences between systems. The receivers of the **SP481E** and **SP485E** have a tri-state enable control pin. A logic LOW on  $\overline{\text{RE}}$  (pin 2) will enable the receiver, a logic HIGH on  $\overline{\text{RE}}$  (pin 2) will disable the receiver.

The receiver for the **SP481E** and **SP485E** will operate up to at least 10Mbps. The receiver for each of the two devices is equipped with the fail-safe feature. Fail-safe guarantees that the receiver output will be in a HIGH state when the input is left unconnected.

# Shutdown Mode SP481E

The **SP481E** is equipped with a Shutdown mode. To enable the Shutdown state, both the driver and receiver must be disabled simultaneously. A logic LOW on DE (pin 3) and a logic HIGH on  $\overline{\text{RE}}$  (pin 2) will put the **SP481E** into Shutdown mode. In Shutdown, supply current will drop to typically  $1\mu\text{A}$ .

#### **ESD TOLERANCE**

The **SP481E** Family incorporates ruggedized ESD cells on all driver output and receiver input pins. The ESD structure is improved over our previous family for more rugged applications and environments sensitive to electro-static discharges and associated transients. The improved ESD tolerance is at least ±15kV without damage nor latch-up.

There are different methods of ESD testing applied:

- a) MIL-STD-883, Method 3015.7
- b) IEC1000-4-2 Air-Discharge
- c) IEC1000-4-2 Direct Contact

The Human Body Model has been the generally accepted ESD testing method for semiconductors. This method is also specified in MIL-STD-883, Method 3015.7 for ESD testing. The premise of this ESD test is to simulate the human body's potential to store electro-static energy and discharge it to an integrated circuit. The simulation is performed by using a test model as shown in *Figure 7*. This method will test the IC's capability to withstand an ESD transient during normal handling such as in manufacturing areas where the ICs tend to be handled frequently.

The IEC-1000-4-2, formerly IEC801-2, is generally used for testing ESD on equipment and

systems. For system manufacturers, they must guarantee a certain amount of ESD protection since the system itself is exposed to the outside environment and human presence. The premise with IEC1000-4-2 is that the system is required to withstand an amount of static electricity when ESD is applied to points and surfaces of the equipment that are accessible to personnel during normal usage. The transceiver IC receives most of the ESD current when the ESD source is applied to the connector pins. The test circuit for IEC1000-4-2 is shown on *Figure 8*. There are two methods within IEC1000-4-2, the Air Discharge method and the Contact Discharge method.

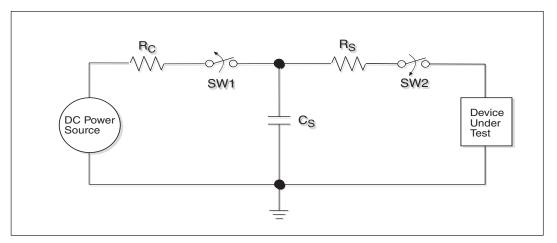


Figure 7. ESD Test Circuit for Human Body Model

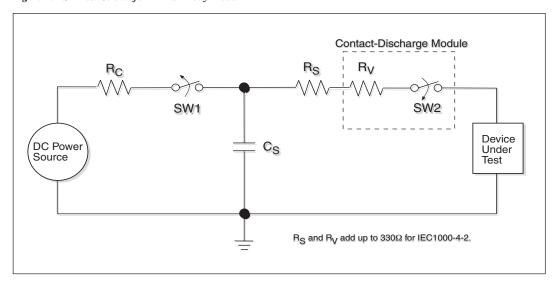


Figure 8. ESD Test Circuit for IEC1000-4-2

With the Air Discharge Method, an ESD voltage is applied to the equipment under test (EUT) through air. This simulates an electrically charged person ready to connect a cable onto the rear of the system only to find an unpleasant zap just before the person touches the back panel. The high energy potential on the person discharges through an arcing path to the rear panel of the system before he or she even touches the system. This energy, whether discharged directly or through air, is predominantly a function of the discharge current rather than the discharge voltage. Variables with an air discharge such as approach speed of the object carrying the ESD potential to the system and humidity will tend to change the discharge current. For example, the rise time of the discharge current varies with the approach speed.

The Contact Discharge Method applies the ESD current directly to the EUT. This method was devised to reduce the unpredictability of the ESD arc. The discharge current rise time is constant since the energy is directly transferred without the air-gap arc. In situations such as hand held systems, the ESD charge can be directly discharged to the equipment from a person already holding the equipment. The current is transferred on to the keypad or the serial port of the equipment directly and then travels through the PCB and finally to the IC.

The circuit model in *Figures 7* and  $\delta$  represent the typical ESD testing circuit used for all three methods. The  $C_S$  is initially charged with the DC power supply when the first switch (SW1) is on. Now that the capacitor is charged, the second switch (SW2) is on while SW1 switches off. The

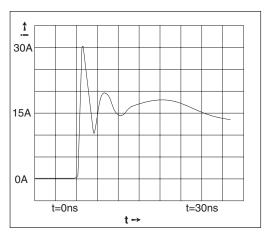


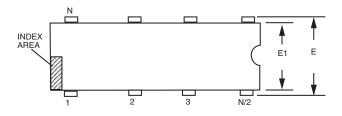
Figure 9. ESD Test Waveform for IEC1000-4-2

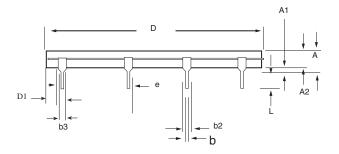
voltage stored in the capacitor is then applied through  $R_S$ , the current limiting resistor, onto the device under test (DUT). In ESD tests, the SW2 switch is pulsed so that the device under test receives a duration of voltage.

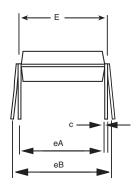
For the Human Body Model, the current limiting resistor ( $R_s$ ) and the source capacitor ( $C_s$ ) are 1.5k $\Omega$  an 100pF, respectively. For IEC-1000-4-2, the current limiting resistor ( $R_s$ ) and the source capacitor ( $C_s$ ) are 330 $\Omega$  an 150pF, respectively.

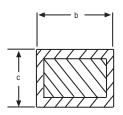
The higher  $C_s$  value and lower  $R_s$  value in the IEC1000-4-2 model are more stringent than the Human Body Model. The larger storage capacitor injects a higher voltage to the test point when SW2 is switched on. The lower current limiting resistor increases the current charge onto the test point.

SP481E, SP485E FAMILY	HUMAN BODY MODEL	Air Discharge	IEC1000-4-2 Direct Contact	Level
Driver Outputs	±15kV	±15kV	±8kV	4 4
Receiver Inputs	±15kV	±15kV	±8kV	



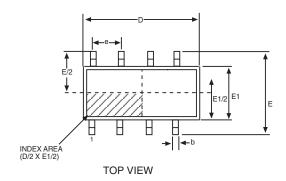


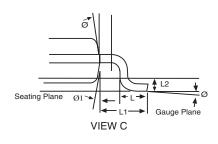


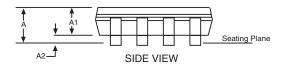


8 PIN PDIP JEDEC MS-001 (BA) Variation							
SYMBOL	MIN	NOM	MAX				
Α	-	-	0.21				
A1	0.15	-	-				
A2	0.115	0.13	0.195				
b	0.014	0.018	0.022				
b2	0.045	0.06	0.07				
b3	0.3	0.039	0.045				
С	0.008	0.01	0.014				
D	0.355	0.365	0.4				
D1	0.005	-	-				
E	0.3	0.31	0.325				
E1	0.24	0.25	0.28				
е	.100 BSC						
eA		.300 BSC					
еВ	-	-	0.43				
L	0.115	0.13	0.15				

Note: Dimensions in (mm)

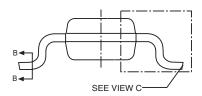


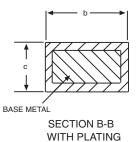




8 Pin NSOIC JEDEC MO-012 (AA) Variation						
SYMBOL	MIN	NOM	MAX			
Α	1.35	-	1.75			
A1	0.1	-	0.25			
A2	1.25	-	1.65			
b	0.31	-	0.51			
С	0.17	-	0.24			
D	4.90 BSC					
E	6.00 BSC					
E1	3.90 BSC					
е		1.27 BSC				
L	0.4	-	1.27			
L1	1.04 REF					
L2	0.25 BSC					
Ø	00	-	80			
ø1	50	-	15°			







### **ORDERING INFORMATION**

Part Number	Top Mark	Temperature Range	Package
SP481ECN	481ECNYYWWH	0°C to +70°C	8-pin NSOIC
SP481ECN/TR	481ECNYYWWH	0°C to +70°C	8-pin NSOIC
SP481ECP	SP481ECPYYWW	0°C to +70°C	8-pin PDIP
SP481EEN	481EENYYWW	40°C to +85°C	8-pin NSOIC
SP481EEN/TR	481EENYYWW	40°C to +85°C	8-pin NSOIC
SP481EEP	SP481EEPYYWW	40°C to +85°C	8-pin PDIP
SP485ECN	485ECNYYWW	0°C to +70°C	8-pin NSOIC
SP485ECN/TR	485ECNYYWW	0°C to +70°C	8-pin NSOIC
SP485ECP	SP485ECPYYWW	0°C to +70°C	8-pin PDIP
SP485EEN	485ECNYYWW	40°C to +85°C	8-pin NSOIC
SP485EEN/TR	485ECNYYWW	40°C to +85°C	8-pin NSOIC
SP485EEP	SP485EEPYYWW	40°C to +85°C	8-pin PDIP
SP485EMN	SP485EMNYYWW	40°C to +125°C	8-pin NSOIC
SP485EMN/TR	SP485EMNYYWW	40°C to +125°C	8-pin NSOIC

Available in lead free packaging. To order add "-L" suffix to part number.

Example: SP485EEN/TR = standard; SP485EEN-L/TR = lead free

/TR = Tape and Reel

Pack quantity is 2500 for Narrow SOIC.





Sipex Corporation

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Date: 02/24/05

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11